Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/660,106	MIURA, TAKAYOSHI	
Examiner	Art Unit	
Stephen Avila	3617	

SEARCHED					
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)						
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